

## 10 MHz rail-to-rail CMOS 16 V operational amplifiers







### **Maturity status link** [TSX920,](https://www.st.com/en/product/TSX920?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502) [TSX921](https://www.st.com/en/product/TSX921?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502), [TSV922,](https://www.st.com/en/product/tsx922?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502) [TSV923](https://www.st.com/en/product/TSX923?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502)



### **Features**

- Rail-to-rail input and output
- Wide supply voltage: 4 V 16 V
- Gain bandwidth product: 10 MHz typ at 16 V
- Low power consumption: 2.8 mA typ per amplifier at 16 V
- Unity gain stable
- Low input bias current: 10 pA typ
- High tolerance to ESD: 4 kV HBM
- Extended temperature range: -40 °C to 125 °C
- Automotive qualification

## **Applications**

- **Communications**
- Process control
- Test equipment

## **Description**

The TSX92x single and dual operational amplifiers (op amps) offer excellent AC characteristics such as 10 MHz gain bandwidth, 17 V/ms slew rate, and 0.0003 % THD+N. These features make the TSX92x family particularly well-adapted for communications, I/V amplifiers for ADCs, and active filtering applications.

Their rail-to-rail input and output capability, while operating on a wide supply voltage range of 4 V to 16 V, allows these devices to be used in a wide range of applications. Automotive qualification is available as these devices can be used in this market segment.

Shutdown mode is available on the single ([TSX920](https://www.st.com/en/product/TSX920?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502)) and dual ([TSV923](https://www.st.com/en/product/TSX923?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502)) versions enabling an important current consumption reduction while this function is active.

The TSX92x family is available in SMD packages featuring a high level of integration. The DFN8 package, used in the [TSV922,](https://www.st.com/en/product/tsx922?ecmp=tt9470_gl_link_feb2019&rt=ds&id=DS9502) with a typical size of 2x2 mm and a maximum height of 0.8 mm offers even greater package size reduction.



# **1 Package pin connections**



**Figure 1. Pin connections (top view)**

MiniSO10 (TSX923)



# **2 Absolute maximum ratings and operating conditions**



#### **Table 1. Absolute maximum ratings (AMR)**

*1. All voltage values, except the differential voltage are with respect to network ground terminal.*

*2. The differential voltage is the non-inverting input terminal with respect to the inverting input terminal.*

*3. Input current must be limited by a resistor in series with the inputs.*

- *4. Rth are typical values.*
- *5. Short-circuits can cause excessive heating and destructive dissipation.*
- *6. According to JEDEC standard JESD22-A114F*
- *7. According to JEDEC standard JESD22-A115A*
- *8. According to ANSI/ESD STM5.3.1*

#### **Table 2. Operating conditions**





## **3 Electrical characteristics**

### **Table 3. Electrical characteristics at VCC+ = 4.5 V with VCC- = 0 V, Vicm = VCC/2, Tamb = 25 °C, and RL = 10 kΩ connected to VCC/2 (unless otherwise specified)**



<span id="page-4-0"></span>



*1. Typical value is based on the Vio drift observed after 1000 h at 125 °C extrapolated to 25 °C using the Arrhenius law and assuming an activation energy of 0.7 eV. The operational amplifier is aged in follower mode configuration (see [Section 5.5 Long term input offset voltage](#page-15-0) [drift](#page-15-0)).*

*2. When used in comparator mode, with high differential input voltage, during a long period of time with VCC close to 16 V and Vicm>VCC/2, Vio can experience a permanent drift of a few mV drift. This phenomenon is notably worse at low temperatures.*



#### **Table 4. Electrical characteristics at VCC+ = 10 V with VCC- = 0 V, Vicm = VCC/2, Tamb = 25 °C, and RL = 10 kΩ connected to VCC/2 (unless otherwise specified)**



<span id="page-6-0"></span>



*1. Typical value is based on the Vio drift observed after 1000 h at 125 °C extrapolated to 25 °C using the Arrhenius law and assuming an activation energy of 0.7 eV. The operational amplifier is aged in follower mode configuration (see [Section 5.5 Long term input offset voltage](#page-15-0) [drift](#page-15-0)).*

*2. When used in comparator mode, with high differential input voltage, during a long period of time with VCC close to 16 V and Vicm>VCC/2, Vio can experience a permanent drift of a few mV drift. This phenomenon is notably worse at low temperatures.*



#### **Table 5. Electrical characteristics at VCC+ = 16 V with VCC- = 0 V, Vicm = VCC/2, Tamb = 25 °C, and RL = 10 kΩ connected to VCC/2 (unless otherwise specified)**



<span id="page-8-0"></span>



*1. Typical value is based on the Vio drift observed after 1000 h at 125 °C extrapolated to 25 °C using the Arrhenius law and assuming an activation energy of 0.7 eV. The operational amplifier is aged in follower mode configuration (see [Section 5.5 Long term input offset voltage](#page-15-0) [drift](#page-15-0)).*

*2. When used in comparator mode, with high differential input voltage, during a long period of time with VCC close to 16 V and Vicm>VCC/2, Vio can experience a permanent drift of a few mV drift. This phenomenon is notably worse at low temperatures.*







**Figure 4. Distribution of input offset voltage at V<sub>CC</sub> = 10 V Figure 5. Distribution of input offset voltage at V<sub>CC</sub> = 16 V** 





































#### **TSX920, TSX921, TSX922, TSX923 Electrical characteristic curves**







**Figure 29. Output impedance vs. frequency in closed loop configuration**

















## <span id="page-15-0"></span>**5 Application information**

### **5.1 Operating voltages**

The TSX92x operational amplifiers can operate from 4 V to 16 V. The parameters are fully specified at 4.5 V, 10 V, and 16 V power supplies. However, parameters are very stable in the full  $V_{CC}$  range. Additionally, main specifications are guaranteed in the extended temperature range from -40 to 125 °C.

### **5.2 Rail-to-rail input**

The TSX92x series is designed with two complementary PMOS and NMOS input differential pairs. The device has a rail-to-rail input and the input common mode range is extended from (V<sub>CC-</sub>) - 0.1 V to (V<sub>CC+</sub>) + 0.1 V. However, the performance of this device is clearly optimized for the PMOS differential pairs (which means from  $(V_{CC_1})$  - 0.1 V to  $(V_{CC+}) - 2 V$ ).

Beyond ( $V_{CC+}$ ) - 2 V, the operational amplifier is still functional but with downgraded performances (see Figure 19). Performances are still suitable for a large number of applications requiring the rail-to-rail input feature. The TSX92x operational amplifiers are designed to prevent phase reversal.

### **5.3 Input pin voltage range**

The TSX92x operational amplifiers have internal ESD diode protections on the inputs. These diodes are connected between the input and each supply rail to protect MOSFETs inputs from electrostatic discharges.

Thus, if the input pin voltage exceeds the power supply by 0.5 V, the ESD diodes become conductive and excessive current could flow through them. To prevent any permanent damage, this current must be limited to 10 mA. This can be done by adding a resistor in series with the input pin (Figure 38). The resistor value has to be calculated for a 10 mA current limitation on the input pins.

#### **Figure 38. Limiting input current with a series resistor**



#### **5.4 Input offset voltage drift over temperature**

The maximum input voltage drift over the temperature variation is defined as the offset variation related to offset value measured at 25 °C. The operational amplifier is one of the main circuits of the signal conditioning chain, and the amplifier input offset is a major contributor to the chain accuracy. The signal chain accuracy at 25 °C can be compensated during production at application level. The maximum input voltage drift over temperature enables the system designer to anticipate the effect of temperature variations.

The maximum input voltage drift over temperature is computed using Equation 1 .

**Equation 1**

$$
\frac{\Delta V_{io}}{\Delta T} = max \left| \frac{V_{io}(T) - V_{io}(25\text{ °C})}{T - 25\text{ °C}} \right|
$$

with T = -40  $^{\circ}$ C and 125  $^{\circ}$ C.

The datasheet maximum value is guaranteed by a measurement on a representative sample size ensuring a  $C_{nk}$ (process capability index) greater than 2.

### **5.5 Long term input offset voltage drift**

To evaluate product reliability, two types of stress acceleration are used:

• Voltage acceleration, by changing the applied voltage

• Temperature acceleration, by changing the die temperature (below the maximum junction temperature allowed by the technology) with the ambient temperature.

The voltage acceleration has been defined based on JEDEC results, and is defined using Equation 2. **Equation 2**

$$
A_{FV} = e^{\beta \cdot (V_S - V_U)}
$$

Where:

 $A_{FV}$  is the voltage acceleration factor

β is the voltage acceleration constant in 1/V, constant technology parameter (β = 1)

 $V<sub>S</sub>$  is the stress voltage used for the accelerated test

 $V_{U}$  is the voltage used for the application

The temperature acceleration is driven by the Arrhenius model, and is defined in Equation 3.

**Equation 3**

$$
A_{\mathsf{FT}} = e^{\frac{E_a}{k} \cdot \left(\frac{1}{T_U} - \frac{1}{T_S}\right)}
$$

Where:

 $A_{FT}$  is the temperature acceleration factor

 $E_a$  is the activation energy of the technology based on the failure rate

k is the Boltzmann constant  $(8.6173 \times 10^{-5} \text{ eV} \cdot \text{K}^{-1})$ 

 $T_U$  is the temperature of the die when  $V_U$  is used (K)

 $T_S$  is the temperature of the die undertemperature stress  $(K)$ 

The final acceleration factor,  $A_F$ , is the multiplication of the voltage acceleration factor and the temperature acceleration factor (Equation 4).

**Equation 4**

$$
A_F = A_{FT} \times A_{FV}
$$

 $A_F$  is calculated using the temperature and voltage defined in the mission profile of the product. The  $A_F$  value can then be used in Equation 5 to calculate the number of months of use equivalent to 1000 hours of reliable stress duration.

**Equation 5**

$$
Monthly = A_F \times 1000 \text{ h} \times 12 \text{ months} / (24 \text{ h} \times 365.25 \text{ days})
$$

To evaluate the op amp reliability, a follower stress condition is used where  $V_{CC}$  is defined as a function of the maximum operating voltage and the absolute maximum rating (as recommended by JEDEC rules). The V<sub>io</sub> drift (in  $\mu$ V) of the product after 1000 h of stress is tracked with parameters at different measurement conditions (see Equation 6).

**Equation 6**

$$
V_{CC} = \text{max} V_{op} \text{ with } V_{icm} = V_{CC} / 2
$$

The long term drift parameter  $(\Delta V_{io})$ , estimating the reliability performance of the product, is obtained using the ratio of the  $V_{io}$  (input offset voltage value) drift over the square root of the calculated number of months (Equation 7).

**Equation 7**

$$
\Delta V_{\text{io}} = \frac{V_{\text{io}} \text{drift}}{\sqrt{\text{(month s)}}}
$$

Where  $V_{io}$  drift is the measured drift value in the specified test conditions after 1000 h stress duration.



## **5.6 Capacitive load**

Driving a large capacitive load can cause stability issues. Increasing the load capacitance produces gain peaking in the frequency response, with overshooting and ringing in the step response. It is usually considered that with a gain peaking higher than 2.3 dB the op amp might become unstable. Generally, the unity gain configuration is the worst configuration for stability and the ability to drive large capacitive loads. Figure 39. Stability criteria with a serial resistor shows the serial resistor (Riso) that must be added to the output, to make the system stable.



#### **Figure 39. Stability criteria with a serial resistor**





### **5.7 High-side current sensing**

TSX92x rail to rail input devices can be used to measure a small differential voltage on a high side shunt resistor and translate it into a ground referenced output voltage. The gain is fixed by external resistance.

**Figure 41. High-side current sensing configuration**



V<sub>out</sub> can be expressed as follows:

#### **Equation 8**

$$
V_{out} = R_{shunt} \times I \left(1 - \frac{R_{g2}}{R_{g2} + R_{f2}}\right) \left(1 + \frac{R_{f1}}{R_{g1}}\right) + I_p \left(\frac{R_{g2} \times R_{f2}}{R_{g2} + R_{f2}}\right) \times \left(1 + \frac{R_{f1}}{R_{g1}}\right) - I_n \times R_{f1} - V_{io} \left(1 + \frac{R_{f1}}{R_{g1}}\right)
$$

Assuming that  $R_{f2}$  =  $R_{f1}$  =  $R_f$  and  $R_{g2}$  =  $R_{g1}$  =  $R_g$ , Equation 8 can be simplified as follows: **Equation 9**

$$
V_{out} = R_{shunt} \times I\left(\frac{R_f}{R_g}\right) - V_{io}\left(1 + \frac{R_f}{R_g}\right) + R_f \times I_{io}
$$

With the TSX92x operational amplifiers, the high side current measurement must be made by respecting the common mode voltage of the amplifier:  $(V_{CC-})$  - 0.1 V to  $(V_{CC+})$  + 0.1 V. If the application requires a higher common voltage please refer to the TSC high side current sensing family.

### **5.8 High-speed photodiode**

The TSX92x series is an excellent choice for current to voltage (I-V) conversions. Due to the CMOS technology, the input bias currents are extremely low. Moreover, the low noise and high unity-gain bandwidth of the TSX92x operational amplifiers make them particularly suitable for high-speed photodiode preamplifier applications.

The photodiode is considered as a capacitive current source. The input capacitance,  $C_{N}$ , includes the parasitic input Common mode capacitance,  $C_{CM}$  (3 pF), and the input differential mode capacitance,  $C_{DIFF}$  (8 pF).  $C_{IN}$  acts in parallel with the intrinsic capacitance of the photodiode,  $C_D$ . At higher frequencies, the capacitors affect the circuit response. The output capacitance of a current sensor has a strong effect on the stability of the op amp feedback loop.

 $C_F$  stabilizes the gain and limits the transimpedance bandwidth. To ensure good stability and to obtain good noise performance,  $C_F$  can be set as shown in Equation 10.

**Equation 10**

$$
C_F\!>\!\sqrt{\frac{C_{IN}+C_D}{2\cdot~\pi\cdot~R_F\cdot~\bar{F}_{GBP}}}\;C_{SMR}
$$

where

- $C_{IN} = C_{CM} + C_{DIFF} = 11$  pF
- $C_{\text{DIFF}}$  is the differential input capacitance: 8 pF typical
- $C_{CM}$  is the Common mode input capacitance: 3 pF typical
- $C_D$  is the intrinsic capacitance of the photodiode
- $C_{\text{SMR}}$  is the parasitic capacitance of the surface mount  $R_F$  resistor: 0.2 pF typical
- FGBP is the gain bandwidth product: 10 MHz at 16 V

 $R_F$  fixes the gain as shown in Equation 11.

#### **Equation 11**

 $V_{OUIT} = R_F x I_D$ 

#### **Figure 42. High-speed photodiode**



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# **6 Package information**

In order to meet environmental requirements, ST offers these devices in different grades of [ECOPACK](https://www.st.com/ecopack) packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com.](http://www.st.com) ECOPACK is an ST trademark.



# **6.1 SOT23-5 package information**

### **Figure 43. SOT23-5 package outline**





#### **Table 6. SOT23-5 mechanical data**







# **6.2 SOT23-6 package information**

### **Figure 44. SOT23-6 package outline**





#### **Table 7. SOT23-6 mechanical data**



## **6.3 MiniSO8 package information**

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**Figure 45. MiniSO8 package outline**



#### **Table 8. MiniSO8 package mechanical data**





# **6.4 SO8 package information**

**Figure 46. SO8 package outline**





**Table 9. SO8 package mechanical data**



## **6.5 DFN8 2x2 package information**

### **Figure 47. DFN8 2x2 package outline**



#### **Table 10. DFN8 2x2 mechanical data**



 $\sqrt{2}$ 

# **6.6 MiniSO10 package information**

### **Figure 48. MiniSO10 package outline**





#### **Table 11. MiniSO10 mechanical data**



<span id="page-25-0"></span>



# **7 Ordering information**





*1. Qualified and characterized according to AEC Q100 and Q003 or equivalent, advanced screening according to AEC Q001 & Q 002 or equivalent.*

## **Revision history**



#### **Table 13. Document revision history**